

TRANSFORMING YIELD INFORMATION OF A SEMICONDUCTOR FABRICATION PROCESS

ABSTRACT

Publishable yield information can be produced by obtaining an actual yield value associated with an integrated circuit (IC) or portion of an IC formed on each one of a plurality of wafers using a semiconductor wafer fabrication process. An average yield value associated with a plurality of ICs or portions of an IC formed on each one of the plurality of wafers using the semiconductor fabrication process is determined. A transformed yield value associated with the IC or portion of an IC is generated using the actual yield value and the average yield value.